

# Search Notes



Application/Control No.

10/030,032

Examiner

DANH C. LE

Applicant(s)/Patent under  
Reexamination

FICHET ET AL.

Art Unit

2617

## SEARCHED

Class	Subclass	Date	Examiner
455	466	10/12/04	DCL
	412.2		
	419		
	414.3		
348	14.02		
	455		
380	210		
	211		

## INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
Interference Search		5/18/06	DCL

## SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
Inventor Name Search (check for double patenting)	10/20/04	DCL
EAST Search updated (US, US PUB, EPO JPO, DERWENT)	5/18/06	DCL